

In this talk, we explore a feature screening process designed for ultra-high dimensional data compromised by measurement error. This method employs the cumulative divergence association measure, originally developed for error-free data. By correcting the bias introduced by measurement errors, our procedure retains all informative features for further statistical analysis with significantly high probabilities. Unlike existing screening methods that deal with measurement error, our bias-corrected screening approach can process a broader range of data, extending beyond those with linear structures. We establish sure independence screening and rank consistency under relatively lenient conditions. The effectiveness of our method is demonstrated through numerical studies and real-world data applications, showcasing its superior performance compared to existing methods.